Nordic Test Forum

TestForum 2026
Tallinn, Estonia

Tuesday, December 1st, 2026

Time	Titles	Speakers or additional info
08:15-08:30	Registration	
08:30-08:40	**Welcome / Introduction**	Knut Båtstoløkken
08:40-09:40	**KeyNote Session**	*Chairman: Knut Båtstoløkken*
08:40-09:40	How cybersecurity and the CRA will change your job as a test engineer	Steve Summers, Emerson Test and Measurement (NI)
09:40-10:20	**Exhibitor Forum:** short presentations	*Chairman: Artur Jutman*
10:20-11:00	Coffee Break / Exhibition	
11:00-12:30	**Session 1: Structural test 1 / Test strategies**	*Chairman: Erik Larsson*
11:00-11:30	1.1 The Evolution of Testing: How AI is revolutionizing the world of electronics testing	Lothar Diez, SPEA
11:30-12:00	1.2 ULTRA technology: A must to meet hyperscalers' test needs	Andrea Romano, Seica
12:00-12:30	1.3 From DFT to Production Confidence: Practical Strategies for Modular, High-Coverage Electronics Test	Vojtech Camfrla, UNITES Systems a.s.
12:30-13:30	Lunch	
13:30-15:00	**Session 2: Structural test 2 / Test Automation**	*Chairman: Paulius Musteikis*
13:30-14:00	2.1 Faster inspection with deeper insight & Intelligent verification station	Chanderkant Vaid, GÖPEL electronic GmbH
14:00-14:30	2.2 Next level thermal imaging for detecting open ends for non-destructive validation testing	Dirk Faber, CN Rood
14:30-15:00	2.3 AI Solution for ICT & AOI and High-Speed AXI	Anthony Wang, TRI Test Research Europe GmbH
15:00-15:40	Coffee Break / Exhibition	
15:40-17:10	**Session 3: IJTAG / Security**	*Chairman: Raimedas Sodaitis*
15:40-16:10	3.1 IJTAG in Practice: Where Interoperability Still Breaks, and What Is Being Done About It	Reginald Waller, Asset Intertech
16:10-16:40	3.2 Security Challenges in Design-for-Test Across the Silicon Lifecycle	Erik Larsson, Lund University
16:40-17:10	3.3 The evolution of CAD formats in the electronics industry	Hermann Reischer, Polar Instruments GmbH
17:10-17:40	Fruit & Refreshments / Exhibition	
17:40-19:00	**Panel debate:**	*Panel moderator: Birger Schneider*
	Cybersecurity, Cyber Resilience Act (CRA) and Other Security Issues in Testing of Electronics	
19:30	**Gala Dinner**	

Wednesday, December 2nd, 2026

Time	Titles	Speakers or additional info
08:30-10:00	**Session 4: Test data analysis**	*Chairman: William Baars*
08:30-09:00	4.1 Test data analysis with WATS Alvea and MCP	Natanya Sukkot, The WATS Company
09:00-09:30	4.2 Finding the Signal in the Noise: Hidden Insights from Manufacturing Test Data	Paul Ioan, Keysight Technologies
09:30-10:00	4.3 PCB Repair and Rework with AI That Knows the Board and Its History	Giorgio Insinga, ARBoard
10:00-10:45	Coffee Break / Exhibition	
10:45-12:15	**Session 5: JTAG based test / RF test**	*Chairman: Mattias Ericsson*
10:45-11:15	5.1 Adopting a Secure Development Process in a Test Engineering Team	Steve Summers, Emerson Test and Measurement (NI)
11:15-11:45	5.2 Using Freely available libraries and tools to enhance JTAG Functional Test	Anthony Sparks, JTAG Technologies
11:45-12:15	5.3 From Model to RF: Practical Prototyping and Validation for Next-Generation Wireless Systems	Aku Wilenius, CN Rood
12:15-13:30	Lunch	
13:30-15:00	**Session 6: AI**	*Chairman: Mats Klarholm*
13:30-14:00	6.1 Why AI is Becoming Essential in Test—and How Nigel Enables It	Steve Summers, Emerson Test and Measurement (NI)
14:00-14:30	6.2 Accelerating Test Development with AI: Keysight's Open Tap Approach and Vision	Xavier Lory, Keysight
14:30-15:00	6.3 AI engineered functional test: agent-controlled instrumentation with MCP interface	Artur Jutman, Testonica
15:00-15:15	Closing Session: TestForum concluding remarks	*Knut Båtstoløkken, Kitron*

Technical Program for TestForum 2026

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